



# **Oxide thin films processing:**

# some examples on how to take advantage of perovskite properties into devices



Workshop OSEPI Villa Clythia - Fréjus du 13 au 17 mai 2024

# **G. Agnus** T. Maroutian, S. Matzen, P. Aubert, F. Pesty, Ph. Lecoeur







- Motivations & approaches
- Focus on MEMS devices
- Material review for Si integration

## 2. <u>Thermal based devices</u>

- Bolometer
- Pressure sensor
- Thermoelectricity



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## 3. <u>Strain based devices</u>

- Focus on the link magnetism/strain
- Results on magnetic field sensing
- Flexoelectricity

## **Conclusion & discussion**















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## Perovskite oxides structure







## Growth and structural properties











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SEM





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## Perovskite oxides processing



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## Perovskite oxides processing

## A critical step => etching

- Large Young Modulus •
- High chemical stability •



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# Exalted amplitude of physical effects



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## Perovskite oxides MEMS

2009 ADVANCED MATERIALS

All-Oxide Crystalline Microelectromechanical Systems: Bending the Functionalities of Transition-Metal Oxide Thin Films

By Luca Pellegrino,\* Michele Biasotti, Emilio Bellingeri, Cristina Bernini, Antonio Sergio Siri, and Daniele Marré





180

¢ /Deg

200

Temperature/ K

270

 $\Delta T_c = 23K$ 

-- LSMO on MEMS -- LSMO on Sub

250

90

150

cps

100

1.2

1.0-0.8

0

100

R/R<sub>Tc</sub> 0.6 04

Full oxide approach

b) Patterning the supporting layer

STO substrate

360

300

- c) Removal of the sacrificial layer



**Consiglio Nazionale** 

delle Ricerche

SPIN

d) Functional layer deposition

#### **Pros:**

- High quality films
- Low complexity of the freestanding stack •

#### Cons:

PLD on freestanding (fragile) substrate ٠

*Opens for films transfer of perovskites* (requirement of wafer scale deposition technique !)



www.advmat.d

## Perovskite oxides MEMS

#### **Integration on Si(100) :** Material review

J. W. Reiner et al., *Adv. Mater.* **2010**, *22*, 2919







## Direct integration of SrTiO<sub>3</sub> (STO) by molecular beam epitaxy

R. McKee et al., Phys. Rev. Lett. 1998, 81, 3014



Strategy :

Focus on STO/Si

- 1. Removing the amorphous silicate layer
- 2. Deposition of a thin poorly crystallized layer of STO that act as oxygen barrier
- 3. Deposition of  $SrTiO_3$  at high temperature/oxygen pressure

#### 1.7% of lattice mismatch with Si (cell rotation of 45°)

#### Growth manage by a few groups in the worl:

Etats-Unis:		
C.B. Eom ( <i>Wisconsin</i> )		
D. Schlom ( <i>Cornell</i> )		
Yale, Texas Univ.		

. . . . .

**Europe:** G. Saint Girons (*INL, France*) J. Fompeyrine (*IBM Zurich, Suisse*) ...

# STO <u>5 nm</u> Si(001)

SrTiO<sub>2</sub>

a<sub>sto</sub> = 3,926 Å

G. Niu et al., Appl. Phys. Lett. 2009, 95, 2009

#### Critical steps

...

- preventing the interfacial silicate layer during the growth at high temperature/ oxygen pressure
- Stichometry difficult to control (Oxygen, Sr/Ti ratio)

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## STO/Si: TEM analysis







Coherent relationship between silicon and SrTiO<sub>3</sub>

STEM @ Saragosse

- Different contrasts between interfacial SrTiO<sub>3</sub> (10's of cells)) et the top SrTiO<sub>3</sub>
- Several types of defects with different sizes

#### **Complex structure**

Changes induces by the PLD growth of active films

#### **Homogeneity**

- Growth of an interfacial SiO<sub>2</sub> layer
- Modification of the crystallinity of SrTiO<sub>3</sub>?
- Strain?



## Manganites on STO/Si

#### **Epitaxy of manganites: La<sub>0.67</sub>Sr<sub>0.33</sub>MnO<sub>3</sub>**







	STO	LSMO
a // plan	3,925	3,925
c ⊥ plan	3,89	3,84
bulk	3,905	3,866

- Interfacial SiO<sub>2</sub> layer
- **STO relaxed** with respect to Si 110 (3,839 Å)
- Coherent epitaxy between LSMO and STO
- LSMO under tensile strain => no relaxation
- STO under tensile strain in plane
   Stoichiometry



## Strain in perovskites on Si

High level of stress in those epitaxial thin films





- Octahedral tilting
- Cation displacement
- Octahedral distortio
   (Jahn-Teller)













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## Strain in perovskites on Si

Deneke et al. Nanoscale Research Letters 2011, 6:621 http://www.nanoscalereslett.com/content/6/1/621  Nanoscale Research Letters a SpringerOpen Journal

#### NANO EXPRESS

**Open Access** 

Rolled-up tubes and cantilevers by releasing SrRuO<sub>3</sub>-Pr<sub>0.7</sub>Ca<sub>0.3</sub>MnO<sub>3</sub> nanomembranes

Christoph Deneke<sup>1,2\*</sup>, Elisabeth Wild<sup>2</sup>, Ksenia Boldyreva<sup>3</sup>, Stefan Baunack<sup>2</sup>, Peter Cendula<sup>2</sup>, Ingolf Mönch<sup>2</sup>, Markus Simon<sup>4</sup>, Angelo Malachias<sup>5</sup>, Kathrin Dörr<sup>36</sup> and Oliver G Schmidt<sup>2</sup>

- ➡ ouvertures par IBE
- ➡ Attaque chimique humide sélective du PrCaMnO<sub>3</sub> avec la solution (HF/HNO<sub>3</sub>/H<sub>2</sub>O)

Volonté d'utiliser cette relaxation de contrainte @ UNIVERSITY OF TWENTE.

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nicrotubes obtained from <100> -oriented trenches defined by optical lithography. The tubes in (b) exhibit an aspect ratio of nearly 1:700.







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## Thermal based devices

## <u>Main idea</u>: generate heat and measure it through TCR



The way you generate/lose heat makes your sensor

Air =>

Photon => Bolometer

- Pressure sensor
- Gas flow sensor
- Accelerometer

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#### 2 families of oxides materials





 $TCR = \frac{1}{R(T)} \frac{dR(T)}{dT}$ 

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## Thermal based devices: free-standing bolometer



Simplified thermal model :

Thin film (R, n)

at  $T=T_0+\Delta T$ 

temperature T<sub>o</sub>

Radiation  $\Lambda P$ 



$$S_V(\omega) = \frac{\eta \times R \times I}{G(1+jw\tau)} \times \frac{1}{R} \frac{dR}{dT}$$

#### For fast and sensitive bolometer, one need:

- High TCR material
- Superconductors YBCO close to the supra-métal
- Manganites LSMO à la transition métal-isolant
- des membranes pour réduire la conductance thermique G et le temps de réponse t = C/G

#### Suspended epitaxial YBaCuO microbolometers fabricated by silicon micromachining: Modeling and measurements

Laurence Méchin<sup>a)</sup> and Jean-Claude Villégier DRFMC/SPSMS/LCP-CEA Grenoble, 17 rue des Martyrs, 38054 Grenoble cedex 9, France

Daniel Bloyet GREYC (URA CNRS 1526)-ISMRA, 6 boulevard Maréchal Juin, 14050 Caen cedex, France





La<sub>0.7</sub>Sr<sub>0.3</sub>MnO<sub>3</sub> suspended microbridges for uncooled bolometers made using reactive ion etching of the silicon substrates

S. Liu<sup>a</sup>, B. Guillet<sup>a</sup>, A. Aryan<sup>a</sup>, C. Adamo<sup>b</sup>, C. Fur<sup>a</sup>, J.-M. Routoure<sup>a</sup>, F. Lemarié<sup>c</sup>, D.G. Schlom<sup>b,d</sup>, L. Méchin<sup>a,\*</sup>

> S. Liu et al. Microelec. Eng. (2012) S. Liu, thèse univ. Caen (2013)





## Thermal based devices: free-standing bolometer



# Free-standing bolometers La<sub>0.7</sub>Sr<sub>0.3</sub>MnO<sub>3</sub> (LSMO)

LSMO/YSZ-based buffered Si par PLD

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*LSMO/STO-CTO/Si par MBE puis PLD* 



## Thermal based devices: free-standing pressure gauge

#### D. Le Bourdais PhD

D. Le Bourdais et al., *J. Appl. Phys.* **2015**, *118*, 124509







Pressure of sensitivity: Thermal dissipation Bridge temperature: depends on P



High pressure: Maximal thermal dissipation Lowest bridge temperature



d



## Thermal based devices: free-standing pressure gauge





D. Le Bourdais et al., *J. Appl. Phys.* **2015**, *118*, 124509







Power consumption reduced by <u>3 orders</u> <u>of magnitude</u>

- Manganites chemical stability
- Low intrinsic noise

A. Lisauskas et al., Appl. Phys. Lett. **77**, 756 (2000)



## Thermal based devices: other sensors?



Flux sensor





#### Accelerometer







Thermal based devices: probing other properties

#### Thermoelectricity

=> Superlattices SrTO<sub>3</sub>/Nb:SrTiO<sub>3</sub> for Si integrated thermoelectrcity







Thèse Yann Apertet (2013)

## **Critical point => managing strain relaxation during the release**



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## Strain based devices

## <u>Main idea</u>: Additional degree of freedom thanks to substrate realease of piezoelectric films





For perpendicular geometry:

$$\frac{\Delta l}{l} = d_{33}^{eff} \cdot \Delta V$$



 ${\rm S}_{\rm ij}$  are the elastic compliances of the film at constant electric field

υ

v : Poisson's ratio of the substrate

Y : Young's modulus of the substrate

K. Lefki and G.M. Dormans, J. Appl. Phys. 76, 1764 (1994)

Freestanding devices => release of substrate clamping

 $d_{33}^{eff} = d_{33}$ 





#### **Extrinsic Magnetoelectric effect (ME):** coupled magnetic and electrical phenomenon via elastic interaction



## Focus on the link magnetism/strain



#### Concerned materials:

#### => Strong link between selected materials and desired device application



Piezoelectric layers: PbZrTiO<sub>3</sub> (PZT) or PbMgNbO<sub>3</sub>-PbTiO<sub>3</sub> (PMN-PT) (large piezoelectric response ) BaTiO<sub>3</sub> (using domain engineering; c to c/a2 multi-domain state S. Geprägs PRB 88 (2013))





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#### Magnetoelectric sensors

N. Nguyen PhD 2018

S. Hem PhD 2023



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#### Magnetoelectric sensors

N. Nguyen PhD 2018

S. Hem PhD 2023





#### > Dynamic response – Methods of study









Q-factor: 64 @ Athmosphere 1000 @ 1 mbar







## Optimizing sensitivity => optimize material quality



#### RESEARCH ARTICLE

# Stress Analysis and Q-Factor of Free-Standing (La,Sr)MnO<sub>3</sub> Oxide Resonators

Nicola Manca, Federico Remaggi, Alejandro E. Plaza, Lucia Varbaro, Cristina Bernini, Luca Pellegrino,\* and Daniele Marré





#### **Higher cristalline quality => Higher quality factor**



## Optimizing sensitivity => optimize material quality



Strain, Young's modulus, and structural transition of EuTiO<sub>3</sub> thin films probed by micro-mechanical methods

Cite as: APL Mater. 11, 101107 (2023); doi: 10.1063/5.0166762 Submitted: 7 July 2023 · Accepted: 18 September 2023 · Published Online: 6 October 2023 Nicola Manca.<sup>1,a</sup> © Caia Tarsi,<sup>2</sup> © Alexei Kalaboukhov,<sup>3</sup> © Francesco Bisio,<sup>1</sup> © Federico Caglieris,<sup>1</sup> © Floriana Lombardi.<sup>3</sup> © Daniele Marté.<sup>1,2</sup> © and Luca Pellegrino' ©

#### Single phase multiferroic EuTiO3

**Opens for higher sensitivity** 





## Other strain based devices



#### Inkjet Pinting

<u>G. Rjinders</u>, *Epitaxial PZT films for MEMS printing applications MRS Bulletin 37 1030 (2012)* 

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**Figure 1.** Principle of (a) a thermal bubble jet print head and (b) a piezoelectrically actuated inkjet print head. Thermal print heads have currently the major share in the microelectromechanical inkjet market for use in small office/home office printers, while piezoelectric print heads are an emerging product in the professional printing arena.



**Figure 2.** Examples (from Reference 84) of industrial printing applications of piezoelectric inkjet (left to right): printed circuit board inner layer, solar cell front side metallization, and 3D printed wheels.







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